

## MOS FIELD EFFECT TRANSISTOR $\mu$ PA1800

#### N-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

#### **DESCRIPTION**

The  $\mu$ PA1800 is a switching device which can be driven directly by a 4.0-V power source.

The  $\mu$ PA1800 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

#### **FEATURES**

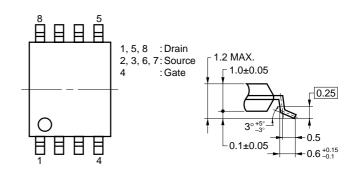
- Can be driven by a 4.0-V power source
- · Low on-state resistance

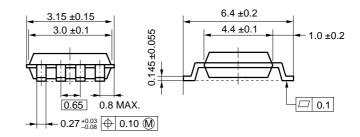
$$\begin{split} &\text{RdS(on)1} = 27~\text{m}\Omega~\text{MAX.}~\text{(VGS} = 10~\text{V, ID} = 3.0~\text{A)} \\ &\text{RdS(on)2} = 39~\text{m}\Omega~\text{MAX.}~\text{(VGS} = 4.5~\text{V, ID} = 3.0~\text{A)} \\ &\text{RdS(on)3} = 45~\text{m}\Omega~\text{MAX.}~\text{(VGS} = 4.0~\text{V, ID} = 3.0~\text{A)} \end{split}$$

#### ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1800GR-9JG	Power TSSOP8

#### PACKAGE DRAWING (Unit: mm)

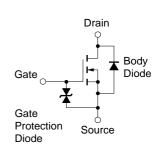




#### ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage	VDSS	30	V
Gate to Source Voltage	Vgss	±20	V
Drain Current (DC)	ID(DC)	±5.0	Α
Drain Current (pulse) Note1	D(pulse)	±20	Α
Total Power Dissipation Note2	PT	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C

#### **EQUIVALENT CIRCUIT**



**Notes 1.** PW  $\leq$  10  $\mu$ s, Duty Cycle  $\leq$  1 %

2. Mounted on ceramic substrate of 50 cm<sup>2</sup> x 1.1 mm

#### Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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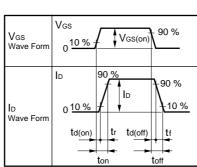


#### **★** ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25 °C)

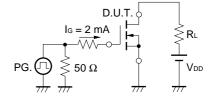
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	Vps = 30 V, Vgs = 0 V			10	μΑ
Gate Leakage Current	Igss	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±10	μΑ
Gate Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.0	1.41	2.0	V
Forward Transfer Admittance	<b>y</b> fs	Vps = 10 V, Ip = 3.0 A	3.0	7.0		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, Ip = 3.0 A		20	27	mΩ
	RDS(on)2	Vgs = 4.5 V, ID = 3.0 A		29	39	mΩ
	RDS(on)3	Vgs = 4.0 V, ID = 3.0 A		32	45	mΩ
Input Capacitance	Ciss	V <sub>DS</sub> = 10 V		680		pF
Output Capacitance	Coss	V <sub>GS</sub> = 0 V		470		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		170		pF
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 15 V		18		ns
Rise Time	tr	ID = 3.0 A		70		ns
Turn-off Delay Time	t <sub>d(off)</sub>	V <sub>GS(on)</sub> = 10 V		60		ns
Fall Time	tf	R <sub>G</sub> = 10 Ω		26		ns
Total Gate Charge	Q <sub>G</sub>	V <sub>DD</sub> = 24 V		23		nC
Gate to Source Charge	Qgs	ID = 5.0 A		2		nC
Gate to Drain Charge	Q <sub>GD</sub>	V <sub>G</sub> S = 10 V		7		nC
Diode Forward Voltage	V <sub>F(S-D)</sub>	IF = 5.0 A, Vgs = 0 V		0.74		V
Reverse Recovery Time	trr	IF = 5.0 A, VGS = 0 V		60		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		80		nC

#### **TEST CIRCUIT 1 SWITCHING TIME**

# PG. $R_{G}$ $T = 1 \mu s$ Duty Cycle $\leq 1 \%$

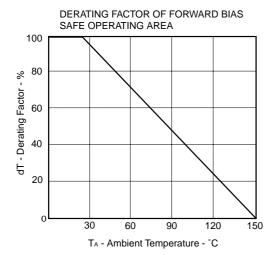


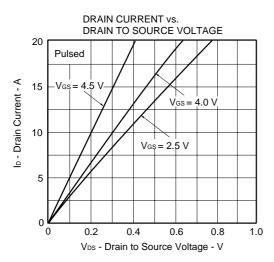
#### **TEST CIRCUIT 2 GATE CHARGE**

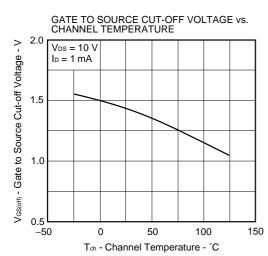


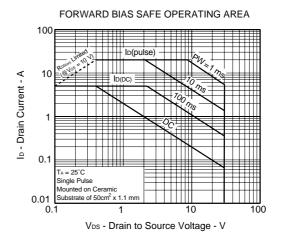


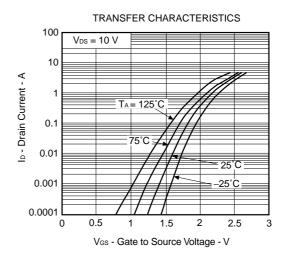
#### **★** TYPICAL CHARACTERISTICS (TA = 25 °C)

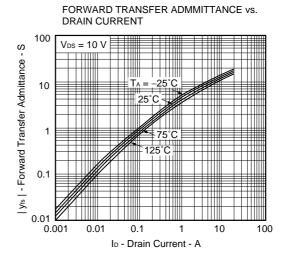




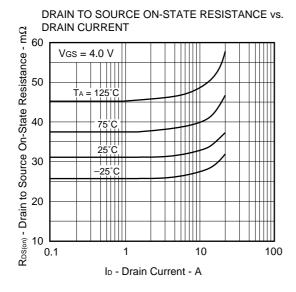


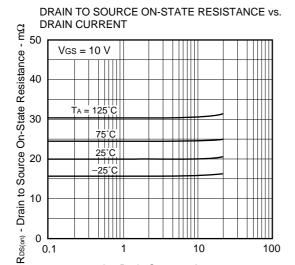




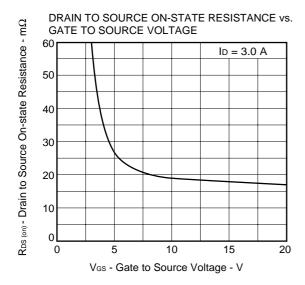


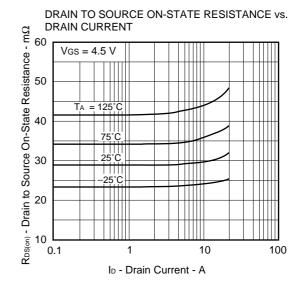
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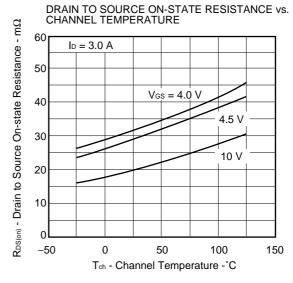


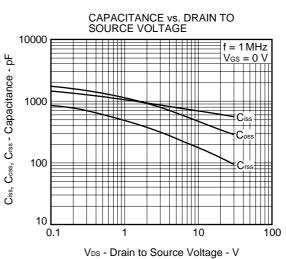


ID - Drain Current - A

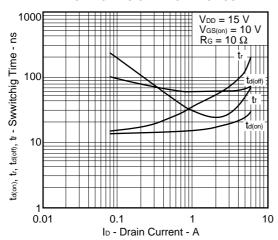




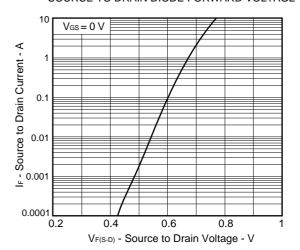




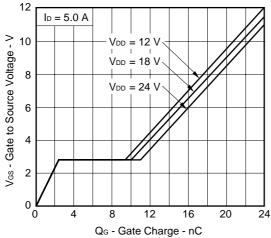
#### SWITCHING CHARACTERISTICS



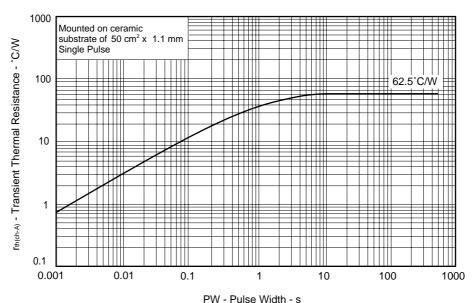
#### SOURCE TO DRAIN DIODE FORWARD VOLTAGE



### DYNAMIC INPUT CHARACTERISTICS



#### TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



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[MEMO]

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